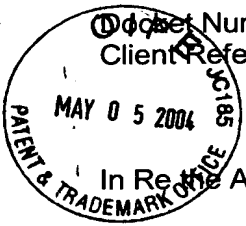


IPW
Document Number: 081468-0305376
Client Reference: P-0362.010-US

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of

VAN BILSEN

Group Art Unit: 2881

Application No.: 10/665,404

Examiner:

Filed: September 22, 2003

Confirmation No.: 4408

For: ALIGNMENT SYSTEMS AND METHODS FOR LITHOGRAPHIC SYSTEM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

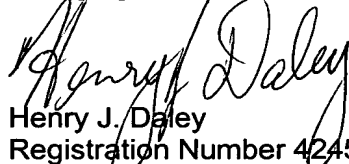
Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed before the mailing date of the first Office Action on the merits in the present application. No certification or fee is required.

The references were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information. The undersigned respectfully notes that copies of U.S. references are not required in applications filed after June 30, 2003.

Respectfully submitted,

PILLSBURY WINTHROP LLP


Henry J. Daley
Registration Number 42459

Date: May 5, 2004

P.O. Box 10500
McLean, VA 22102
Telephone: (703) 905-2000
Facsimile: (703) 905-2500



Atty.
Dkt. No.

M#

Client Ref.

0305376

P-0362.010-US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Frank VAN BILSEN

Appln. No.: 10/665,404

Filing Date: September 22, 2003

Examiner:

Group Art Unit: 2881

Date: May 5, 2004

Page

1

of

1

U.S. PATENT DOCUMENTS

Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR	6,420,791 B1	07/2002	HUANG et al.			
	BR	2002/0158193 A1	10/2002	SEZGINER et al.			
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						
	MR						
	NR						
	OR						
	PR						
	QR						
	RR						

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name		English Abstract		Translation Readily Available	
							Enclosed	No	Enclose	No
	SR									
	TR									
	UR									
	VR									
	WR									
	XR									

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

	YR									
	ZR									
	AAR									
	BBR									
	CCR									

Examiner

Date Considered:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.